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Meet Helio Castroneves, three time Indy 500® Champion and driver of the #3 Hitachi Team Penske Chevy Dallara, at the Hitachi Booth #1304 on Tuesday, August 6th. Enter to win an autographed #3 Hitachi diecast model car.

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M&M 2013 Booth #1304

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Microscopy & Microanalysis

The Official M&M 2013 Meeting and Program Guide Indianapolis, Indiana, USA • August 4–8, 2013



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